

# Design pattern-enabled object-oriented metrics

Khashayar Khosravi

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Département d'informatique et de recherche opérationnelle

Université de Montréal



# Outline

- Why do we need design patterns?
- Are they theoretical or practical?
- Our methodology to get an answer
- Our problems
- Conclusion



# Why do we need design patterns?

- Why do some programmers write code

- 10 times faster than others?
- That executes 10 times faster than others?
- That has 1/10 as many bugs as others?

[Keutzer, 2003]

- One thing expert designers **know not to do** is solve every problem from first principles

- Rather reuse solutions that have worked for them in the past
- When they find a good solution they reuse it again and again, such experience makes them experts

[E. Gamma *et al.*]



# Design patterns

- Help software developers
  - Choose design alternatives
  - Document and maintain
  - Standardize terminology
  - Make object-oriented software more
    - Reusable
    - Flexible
    - Modular
    - Understandable



# Question

- Are design patterns only theoretical or are they practical too?



# Problems with design patterns

- Difficult to learn design patterns just by reading the “design patterns book”

[B. Wydaeghe, K. Verchaeve, B. Michiels, B. V. Damme, E. Arckens, and V. Jonckers]

- Some programs written with design patterns are too **complicated** and **error prone**

[M. tatsubori and S. Chiba]

- Programs with **comments** are more understandable when you use design patterns

[M. tatsubori and S. Chiba]

- Some object-oriented design patterns are more **complicated**

[G. Baumgartner, K. Laufer, and F. Russo]



B. Wydaeghe, K. Verchaeve, B. Michiels, B.  
V. Damme, E. Arckens, and V. Jonckers

■ Editor

- 50,000 lines of code
- 173 classes
- Developed, installed on different platforms

■ Design patterns

- Model-View-Controller
- Observer
- Visitor
- Iterator
- Bridge
- Façade
- Chain of Responsibility

B. Wydaeghe, K. Verchaeve, B. Michiels, B. V. Damme, E. Arckens, and V. Jonckers

	Modularity	Flexibility	Understandability		Reusability
			Expert	Layman	
MVC	+	+	+	-	++
Observer	0	+	0	-	+
Visitor	0	+	0	-	+
Iterator	0	+	0	-	+
Bridge	+	+	+	+	++
Facade	+	+	+	+	++
Chain of responsibility	-	+	0	+	0





# Peter Wendorf

- 50 programmers
- Code Size
  - 800 KLOC C++
  - 200 KLOC PL/SQL
- Design patterns
  - Proxy
  - Observer
  - Bridge
  - Command
- 8 years of experience in software engineering



# Peter Wendorf

## ■ Dilemma of design patterns

### – Proxy

- Use it for more **flexibility**, **access control**, and **performance** but in most cases these future needs never materialized
- Increase the number of classes (and usually files) ⇒ Increases **size** and **complexity**
- Overload preprocessing and post-processing for requests to classes
- Make debugging much harder

### – Bridge

- Change is so hard
- Without good **documentation**, understanding is not possible

### – Command pattern

- **Additional function** that are never required
- Requirement was about 100 elementary operations in sequences on a set of data that should be read from a database, but with command pattern architecture grew into a very **complex** software



# Peter Wendorf

## ■ Cost of removal

### – Proxy

- Remove **3 out of 7** proxy patterns, reduce size by 200 LOC out of 3000 LOC

### – Observer

- New design and implementation of the GUI

### – Bridge

- Merge two classes in one
- Remove **2 out of 3** bridge patterns, reduce size by 190 out of 1400 LOC



# To be, or not to be?

```
public class Welcome {  
    public static void main(final String args[]) {  
        System.out.println("Hello World!");  
    }  
}
```



# Questions

- How can we judge design patterns?
- Are problems from design patterns themselves or from misusing design patterns?



# Measurement

- Identify the object
- Each classes of objects have two types of attribute
  - Internal
  - External
- Measure characterized in two ways
  - Direct measure (modularity)
  - Indirect measure (maintainability)



# Software Quality Models

- Quality models define software qualities as a hierarchy
  - Quality Factors: Represent a **behavioral characteristics** (Maintainability)
  - Quality Characteristic: Attribute of a **quality factor** that relates to software production and design (Analyzability)
  - Quality Metrics: Measure of some aspect of a quality characteristic (N\_STMTS )



# Our methodology

(1/2)

- Evaluate quality characteristic models
  - Find the best definitions for metrics
  - Find the right values for each metrics (numerical result)
  - Find the right metrics for each quality characteristic
  - Find the best characteristics for each quality factors





# Our methodology

(2/2)

- Evaluate design patterns
  - Measure quality characteristic of different types of design patterns
  - Assess **flexibility**, **reusability**, **modularity**, and **understandability** of programs implemented with design patterns
  - Measure quality characteristic of programs **with** and **without** design patterns
  - Ultimately compare the results of both measurements



# Tools for quality evaluation

- Quality factors
  - Standard factors (6 definitions by ISO)
  - Others
- Quality characteristic of software systems
  - Standard characteristic (21 definitions by ISO)
  - Others
- Metrics: Tools to evaluate characteristic of software
  - Standard metrics (30 metrics by ISO)
  - Others

# Control Graph Metrics (McCabe)

Label	mnemonic	Format	Min	max
Number of edges	N_EDGES	I	1	50
Number of nodes	N_NODES	I	1	50
Cyclomatic number	VG	I	1	50
Number of entry nodes	N_IN	I	1	1
Number of exit nodes	N_OUT	I	1	1
Essential complexity	ESS_CPI	I	1	1
Design complexity	DES_CPX	I	1	10

# Textual metrics (Halstead)

Label	Mnemonic	Format	Max	Min
Total operand occurrences	TOT_OPND	I	1	152
Different operators	DIFF_OPND	I	1	38
Total operators occurrences	TOT_OPTR	I	2	198
Different operators	DIFF_OPTR	I	2	18
Program length	PR_LGTH	I	3	350
Vocabulary size	VOC_SZ	I	3	58
Program size	PR_SZ	F	2:00	274:48
Program Volume	PR_VOL	F	4.75	2032.58
Intelligence content	INTELL	F	4.75	1255.98
Estimated number of errors	N_ERRORS	F	0.00	0.95
Program level	PR_LVL	F	0.027	1.00
Program difficulty	PR_CPXTY	F	1.00	36.00
Mental effort	EFFORT	F	4.75	73172.68
Program time	CODE_T	F	0.26	4065.15
Language level	LANG_LVL	F	1.56	1255.98

### Control graph metrics (others)

Label	Mnemonic	Format	Max	Min
Number of unconditional jump (GOTO)	UNCOND_JUMP	I	0	0
Number of exits of condition structures	COND_STRUCTURE	I	0	1

### Basic count

Label	Mnemonic	Format	Max	Min
Number of statements	N_STMTS	I	0	50
Number of comments	N_COM	I	0	10

### Call metrics

Label	Mnemonic	Format	Max	Min
Direct called components	DRCT_CALLS	I	0	9

### User defined metrics

Label	Mnemonic	Format	Max	Min
Number of nested level	$N\_NEST = MAX\_LVLS - 1$	I	0	4
Vocabulary frequency	$VOC\_F = PR\_LGTH / VOC\_SZ$	F	1.00	4.0
Average size of statements	$AVG\_S = PR\_LGTH / N\_STMTS$	F	3.00	7.00



# Others

- Correctness
  - Traceability
  - Completeness
  - Consistency
- Reliability
  - Consistency
  - Accuracy
  - Error tolerance
- Efficiency
  - Execution efficiency
  - Storage efficiency
- Integrity
  - Access control
  - Access audit

# ISO

- Reliability
  - Suitability
  - Accuracy
  - Interoperability
  - Security
- Efficiency
  - Time behavior
  - Resource behavior



# Others

- Usability
  - Operability
  - Training
  - Communicativeness
- Maintainability
  - Simplicity
  - Conciseness
  - Self descriptiveness
  - Modularity
- Testability
  - Simplicity
  - Instrumentation
  - Self descriptiveness
  - Modularity

# ISO

- Usability
  - Understandability
  - learnability
  - Operability
- Maintainability
  - Analyzability
  - Changeability
  - Stability
  - Testability



# Others

- Flexibility
  - Self descriptiveness
  - Expendability
  - Generality
  - Modularity
- Portability
  - Self descriptiveness
  - Software system independence
  - Machine independence
- Reusability
  - Generality
  - Modularity
  - Software system independence
  - Machine dependence
- Interoperability
  - Modularity
  - Communications commonality
  - Data commonality

# ISO

- Functionality
  - suitability
  - accuracy
  - interoperability
  - security
- Portability
  - Adaptability
  - Installability
  - Conformance
  - Replaceability





# Definition of quality

## ■ Maintainability

### – Analyzability

- $25*VG + 25*N\_STMTS + 25*AVG\_S$

### – Changeability

- $25*AVG\_S + 25*N\_NEST + 25*UNCOND\_JUMP + 25*VOC\_F$

### – Stability

- $25*N\_IN + 25*N\_OUT + 25*DRCT\_CALLS + 25*UNCOND\_JUMP$

### – Testability

- $25*COND\_STRUCT + 25*N\_NEST + 25*UNCOND\_JUMP + 25*VG$

## ■ Value rate

– EXCELLENT: 99 - 100

– GOOD: 66 - 99

– FAIR: 33 - 66

– POOR: 0 - 33



# Theoretical problems

- Different definitions for
  - Metrics
  - Quality characteristics
  - Quality factors
- Difficult to find the best definitions for quality factors

# Theoretical problems

## Henderson-Sellers LCOM\*

Consider a set of  $m$  methods,  $M_1, M_2, \dots, M_m$

The methods access  $a$  data attributes,  $A_1, A_2, \dots, A_a$

Let  $a(M_k)$  = number of attributes accessed by method  $M_k$

Let  $m(A_k)$  = number of methods that access data  $A_k$

Then

$$LCOM^* = \frac{\left( \frac{1}{a} \sum_{j=1}^a m(A_j) \right) - m}{1 - m}$$

If each method accesses all attributes then  $m(A_k) = m$  so

$$\begin{aligned} LCOM^* &= \frac{\left( \frac{1}{a} \sum_{j=1}^a m \right) - m}{1 - m} \\ &= \frac{(m) - m}{1 - m} \\ &= 0 \end{aligned}$$

If each method accesses only one attribute and a different attribute then we have:

$$\begin{aligned} LCOM^* &= \frac{\left( \frac{1}{a} \sum_{j=1}^a m \right) - m}{1 - m} \\ &= \frac{\left( \frac{1}{a} \right) - m}{1 - m} \\ &= 1 \end{aligned}$$

So at maximum cohesion  $LCOM^* = 0$

At Henderson-Sellers' "minimum cohesion"  $LCOM^* = 1$

## Lack of Cohesion (LCOM)

-Measures the cohesion or lack of a class; evaluate the dissimilarity of methods in a class by instance variables or attributes.

-LCOM is measured by counting the number of pairs of methods that have no attributes in common, minus the number of methods that do. A negative difference corresponds to LCOM value of zero.

-Low cohesion is a sign of high complexity, and shows that the class can be subdivided. High cohesion indicates simplicity and high potential for reuse.

Example:

Device
type:int
reading:int
mode:boolean
compute(x:int,y:int):int
update(a:int):int
test():int

```

Class Device {
    int reading; type;
    boolean mode=false;

    public int update (int a) {return a + reading; }
    public int compute(int x, int y) {return x*y*type - reading;}
    public void test (int t) { if t ==1 mode=true; }
}
    
```

$$LCOM(Device) = 2 - 1 = 1$$

## Lack of Cohesion in Method: (LCOM)

**Definition:** The number of different methods within a class that reference a given instance variable.

**Facts:**

- Encapsulation is promoted by the use of cohesive methods within a class.
- Classes that should be split into smaller classes are ones that have a lack of cohesion.
- Flaws in the design of classes can be identified by any measure of disparateness of methods.
- Errors are more likely to occur in the development process when there is complexity caused by low cohesion.

**How to figure this out:**

Find the number of methods that are in a class that reference a given instance variable by searching from the root node of the class to the last child.

## Chidamber and Kemerer (1993) LCOM

Let  $C$  be a class, with methods  $M_1, M_2, \dots, M_m$

Let  $I_k$  = the set of instance variables used by method  $M_k$

Let  $P = \{ (I_k, I_j) \mid I_k \text{ and } I_j \text{ do not intersect} \}$

Let  $Q = \{ (I_k, I_j) \mid I_k \text{ and } I_j \text{ do intersect} \}$

If  $|P| > |Q|$  then

$$LCOM = |P| - |Q|$$

else

$$LCOM = 0$$



# Practical problems

- Combination of metrics to implement one characteristics
- Some characteristics can be evaluated by experts only
- Implementation of quality characteristics with standard metrics
- Implementation of metrics



# Example: Practical problems

## Definition of characteristics

- **Usability (ISO)**

- Operability
- Training
- Communicativeness

- **Usability (McCall)**

- Understandability
- Learnability
- Operability

- **Portability (ISO)**

- Adaptability
- Installability
- Conformance
- Replaceability

- **Portability (TRW)**

- Device independence
- Completeness

- **Portability (McCall)**

- Self descriptiveness
- Software system independence
- Machine independence



# Example: Practical problems

ISO/IEC TR 9126-2:2003(E) External Suitability metrics

## Functional adequacy

$$X = 1 - A / B$$

A = Number of functions in which problems are detected in evaluation

B = Number of functions evaluated

$0 \leq X \leq 1$   
(The closer to 1.0, the more adequate)

## Functional implementation completeness

$$X = 1 - A / B$$

A = Number of missing functions detected in evaluation

B = Number of functions described in requirement specifications

$0 \leq X \leq 1$   
(The closer to 1.0, the more adequate)



## From that point on...

- Select the best metrics
- Evaluate quality characteristics with the metrics (and experts)
- Find best model for design patterns
- Implement enough programs with and without design patterns
- Evaluate design pattern quality characteristics for all design patterns



# Conclusion

- Why do we need design patterns?
  - It is depend on what we are doing...
- Are they theoretical or practical?
  - It is depend on the type of software and models of design patterns
- Our methodology to get the answer
  - Apply quality characteristics models on design pattern models
  - Develop a suite of programs with and without design patterns and measure their quality characteristics
- Our problems
  - What are the best definitions for
    - Software quality factors
    - Quality characteristic
    - Software metrics





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# Thank you for your attention

■ Any Comments?

■ Any Question?